

# MOS FIELD EFFECT TRANSISTOR

## 2SK3571

### SWITCHING

#### N-CHANNEL POWER MOS FET

#### DESCRIPTION

The 2SK3571 is N-channel MOS FET device that features a low on-state resistance and excellent switching characteristics, designed for low voltage high current applications such as DC/DC converter with synchronous rectifier.

#### FEATURES

- 4.5V drive available.
- Low on-state resistance,  
 $R_{DS(on)1} = 9.0 \text{ m}\Omega \text{ MAX. (} V_{GS} = 10 \text{ V, } I_D = 24 \text{ A)}$
- Low gate charge  
 $Q_G = 21 \text{ nC TYP. (} V_{DD} = 16 \text{ V, } V_{GS} = 10 \text{ V, } I_D = 48 \text{ A)}$
- Built-in gate protection diode
- Surface mount device available

#### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ )

Drain to Source Voltage ( $V_{GS} = 0 \text{ V}$ )	$V_{DSS}$	20	V
Gate to Source Voltage ( $V_{DS} = 0 \text{ V}$ )	$V_{GSS}$	$\pm 20$	V
Drain Current (DC) ( $T_C = 25^\circ\text{C}$ )	$I_{D(DC)}$	$\pm 48$	A
Drain Current (pulse) <b>Note</b>	$I_{D(pulse)}$	$\pm 192$	A
Total Power Dissipation ( $T_A = 25^\circ\text{C}$ )	$P_{T1}$	1.5	W
Total Power Dissipation ( $T_C = 25^\circ\text{C}$ )	$P_{T2}$	40	W
Channel Temperature	$T_{ch}$	150	$^\circ\text{C}$
Storage Temperature	$T_{stg}$	-55 to +150	$^\circ\text{C}$

**Note**  $PW \leq 10 \mu\text{s}$ , Duty Cycle  $\leq 1\%$

#### ★ ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3571	TO-220AB
2SK3571-S	TO-262
2SK3571-ZK	TO-263
2SK3571-Z	TO-220SMD <b>Note</b>

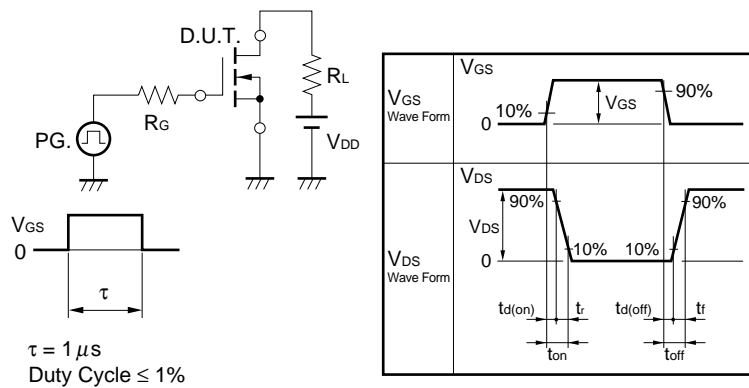
**Note** TO-220SMD package is produced only in Japan.

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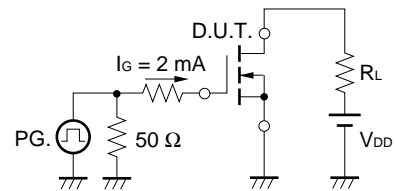
**ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25°C)**

Characteristics	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Zero Gate Voltage Drain Current	I <sub>bss</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			10	μA
Gate Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μA
Gate Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.5		2.5	V
Forward Transfer Admittance	y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 24 A	11			S
Drain to Source On-state Resistance	R <sub>DS(on)1</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 24 A		7.0	9.0	mΩ
	R <sub>DS(on)2</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 18 A		10	16	mΩ
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 10 V		1100		pF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V		450		pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1 MHz		160		pF
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 24 A		13		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V		5		ns
Turn-off Delay Time	t <sub>d(off)</sub>	R <sub>G</sub> = 10 Ω		40		ns
Fall Time	t <sub>f</sub>			9		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DD</sub> = 16 V		21		nC
Gate to Source Charge	Q <sub>GS</sub>	V <sub>GS</sub> = 10 V		4.2		nC
Gate to Drain Charge	Q <sub>GD</sub>	I <sub>D</sub> = 48 A		5		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> = 48 A, V <sub>GS</sub> = 0 V		1.0		V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 48 A, V <sub>GS</sub> = 0 V		41		ns
Reverse Recovery Charge	Q <sub>rr</sub>	di/dt = 100 A/μs		27		nC

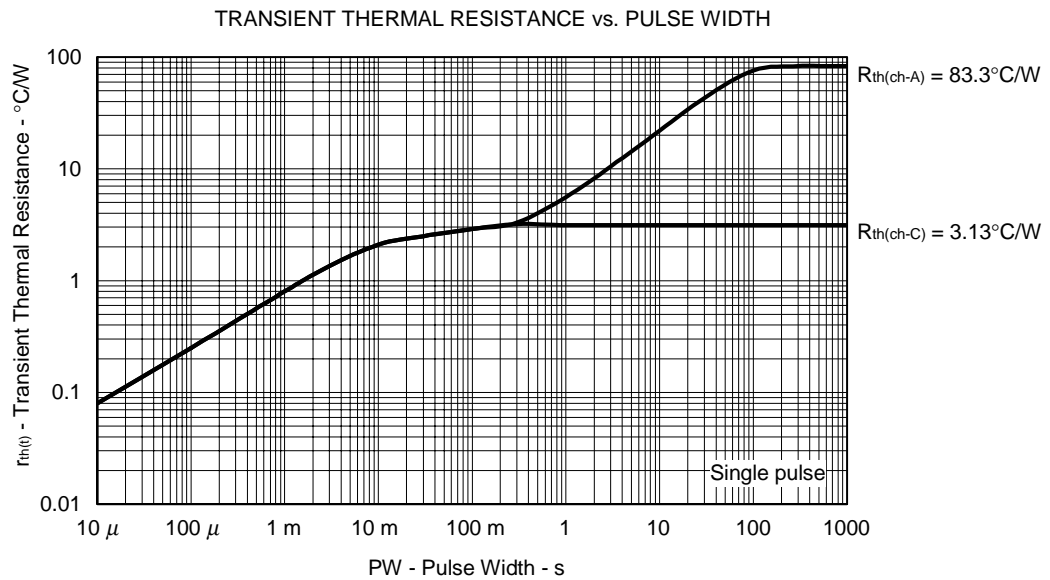
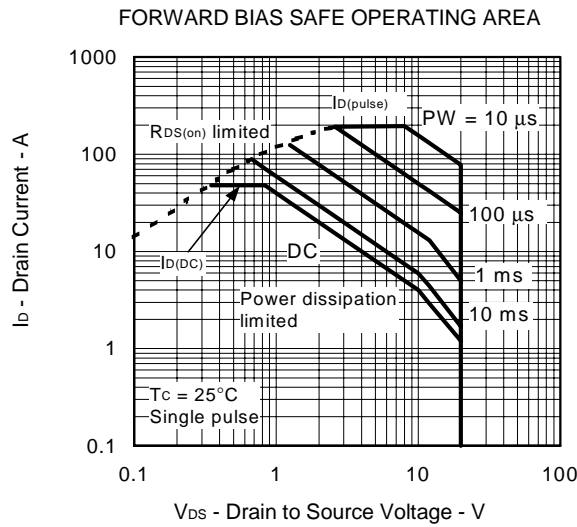
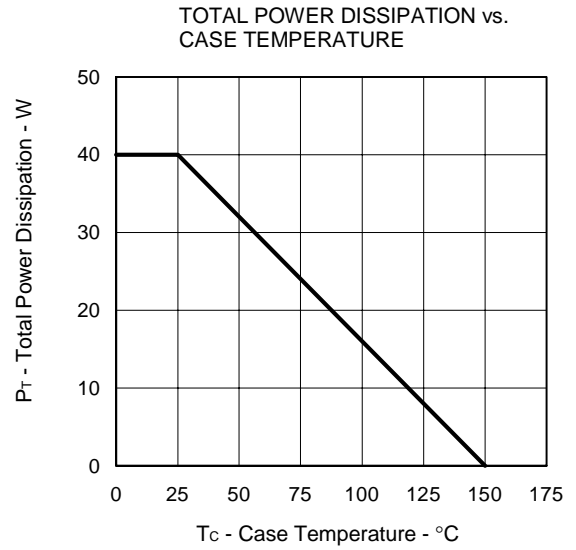
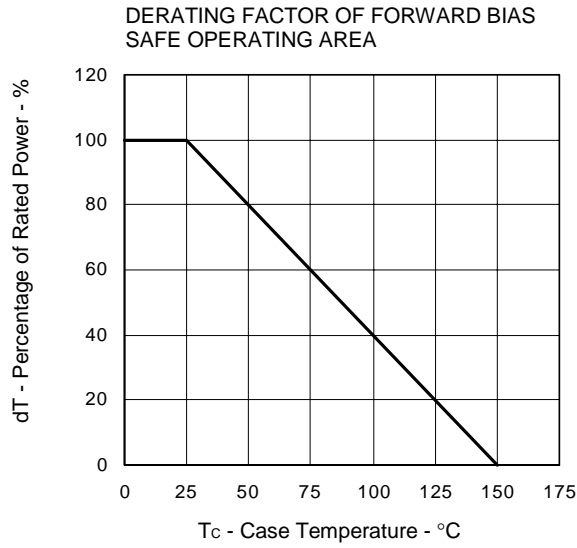
★ TEST CIRCUIT 1 SWITCHING TIME



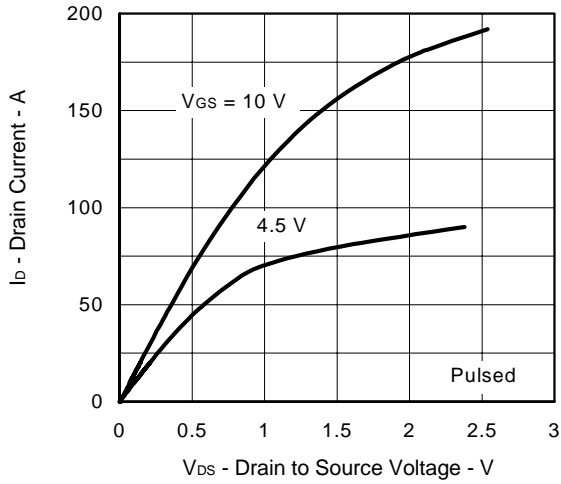
TEST CIRCUIT 2 GATE CHARGE



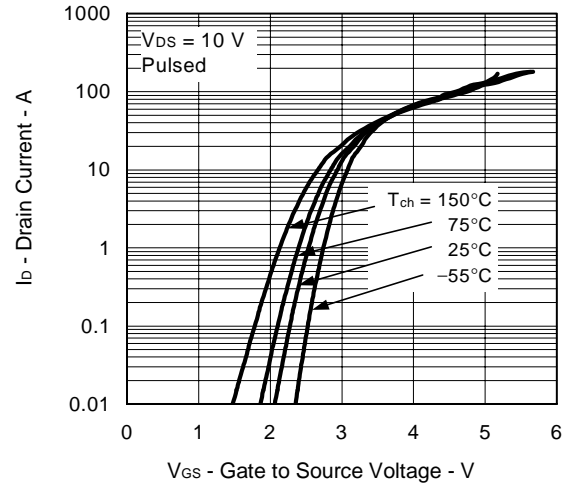
★ TYPICAL CHARACTERISTICS (T<sub>A</sub> = 25°C)



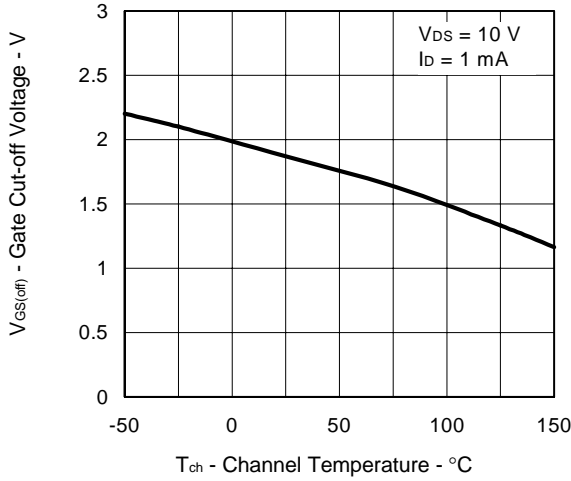
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



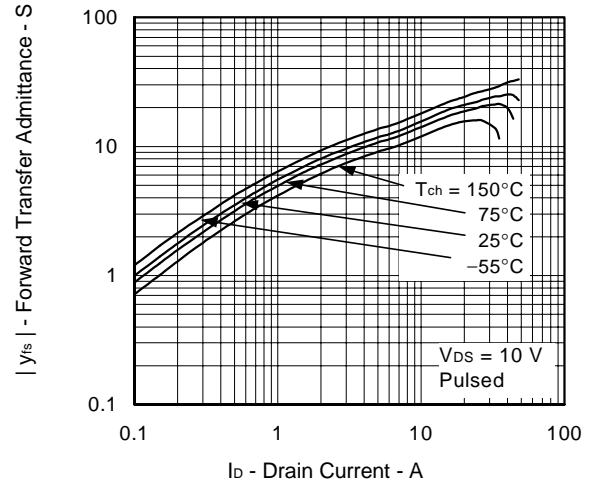
FORWARD TRANSFER CHARACTERISTICS



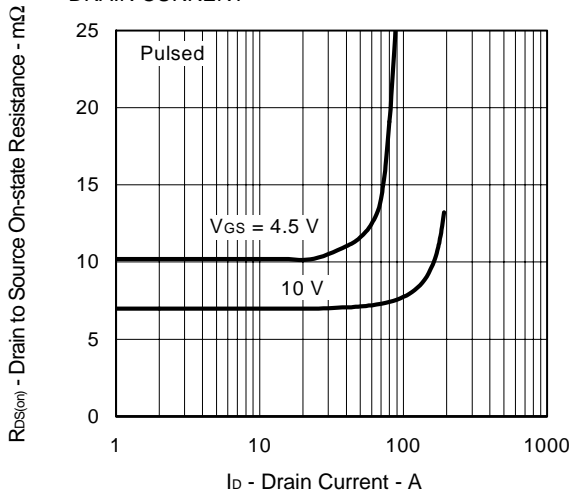
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



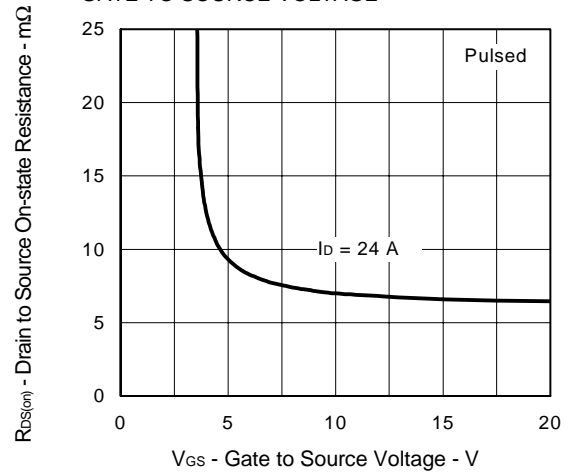
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



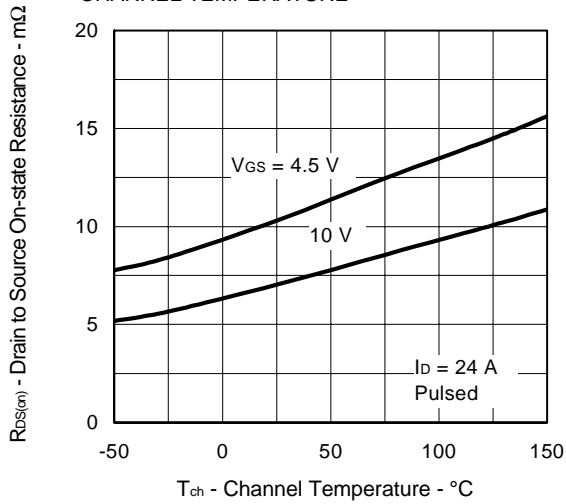
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



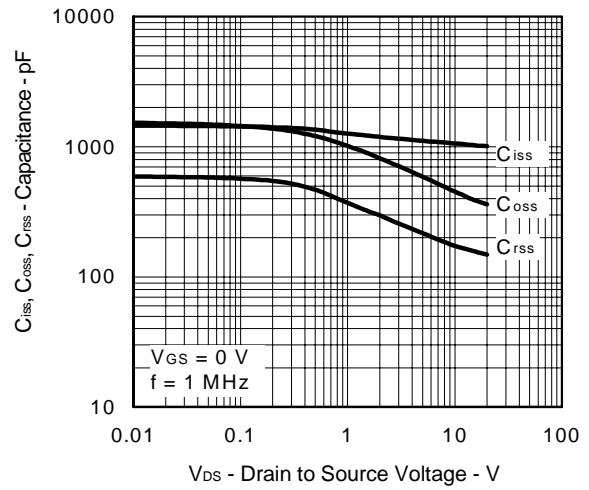
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



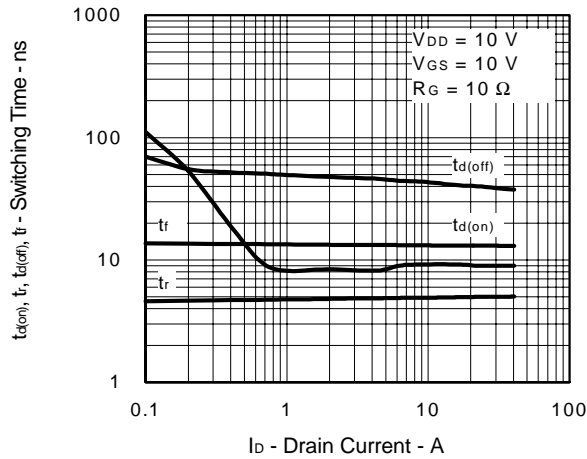
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



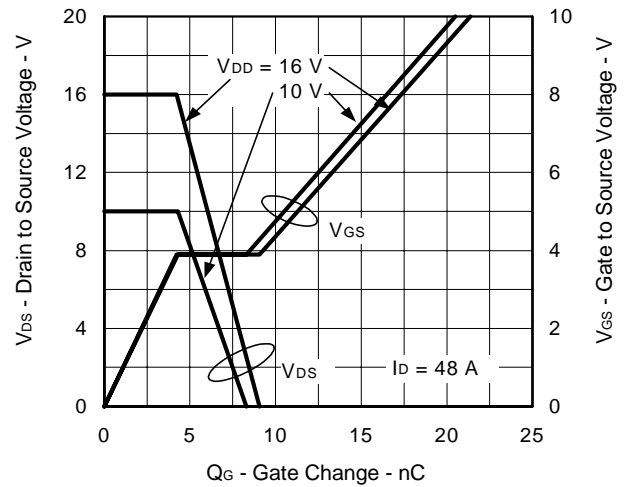
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



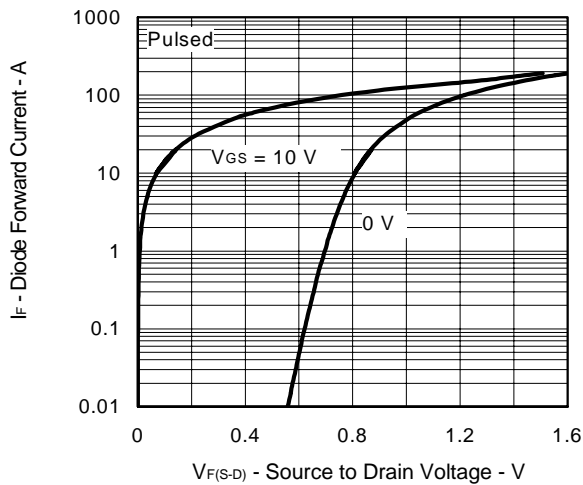
SWITCHING CHARACTERISTICS



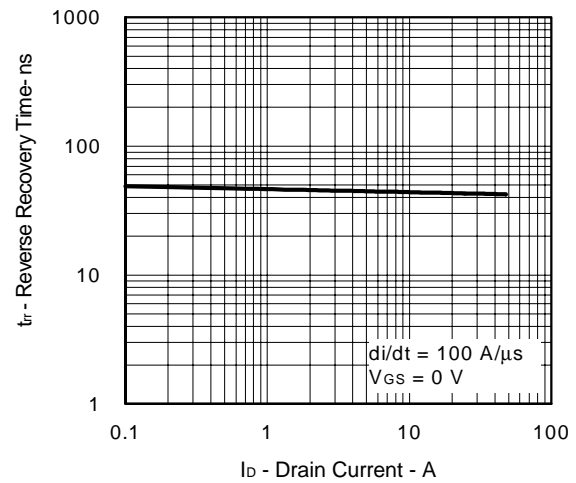
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE

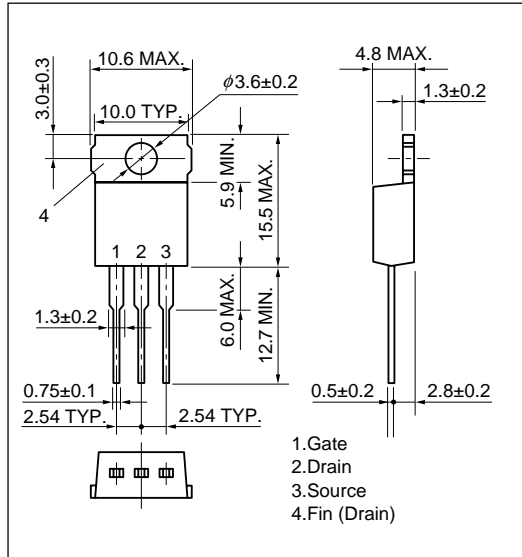


REVERSE RECOVERY TIME vs. DRAIN CURRENT

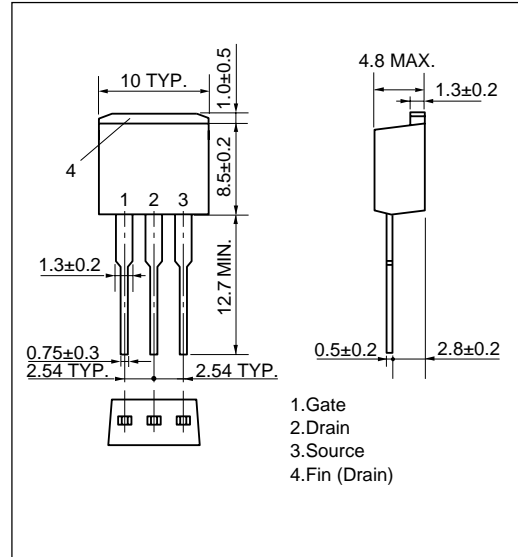


★ PACKAGE DRAWINGS (Unit: mm)

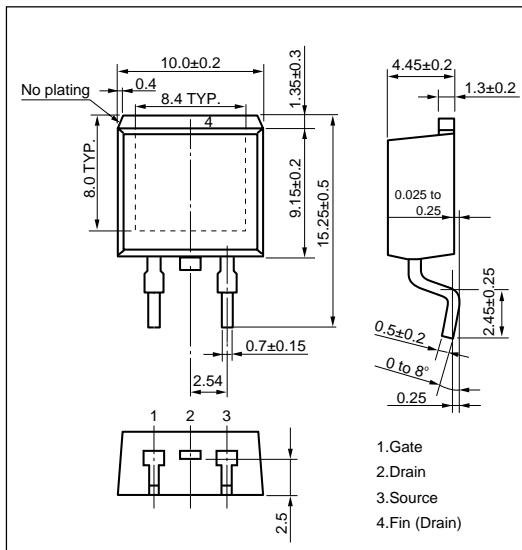
1) TO-220AB (MP-25)



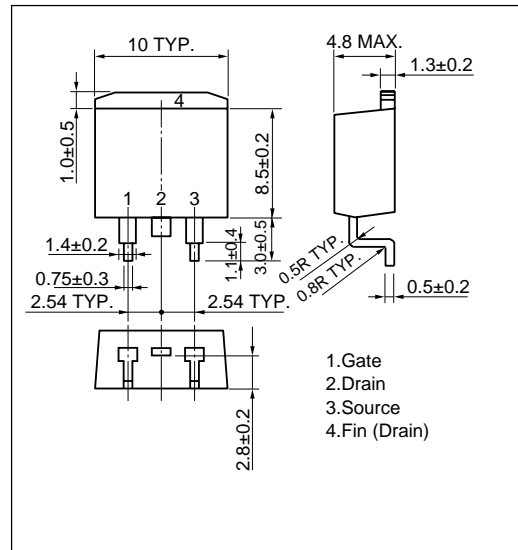
2) TO-262 (MP-25 Fin Cut)



3) TO-263 (MP-25ZK)

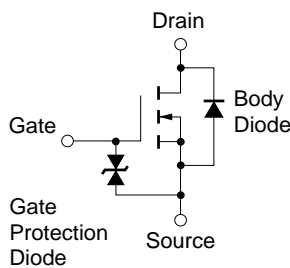


4) TO-220SMD (MP-25Z) **Note**



**Note** This package is produced only in Japan.

EQUIVALENT CIRCUIT



**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

[MEMO]

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